

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	8	buxton-paul\$.in.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/01 09:04
L2	12	tabor-eric\$.in.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/01 09:04
L3	19	martin-emilio\$.in.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/01 09:04
L4	3	zalzala-ali\$.in.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/01 09:05
L5	14	test with advantage\$.as.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/01 09:11
L7	920	702/183.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/01 09:59
L8	404	tester and (component ic wafer chip lot) and ((fabricat\$3 manufactur\$3) with process) and diagnostic and (test with data)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/01 11:05
L9	18	tester and (component ic wafer chip lot) and ((fabricat\$3 manufactur\$3) with process) and diagnostic and (test with data) and (electrical with data) and (corrective with action)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/01 11:08